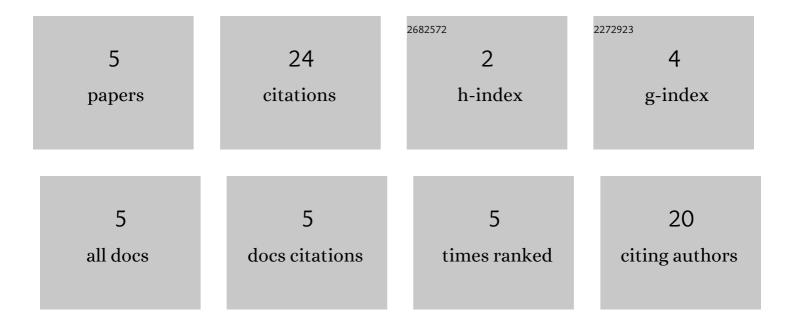
Koichiro Saga

List of Publications by Year in descending order

Source: https://exaly.com/author-pdf/4451412/publications.pdf Version: 2024-02-01



#	Article	IF	CITATIONS
1	<i>(Invited) </i> Metallic Contamination Issues in Advanced Semiconductor Processing. ECS Transactions, 2018, 86, 113-124.	0.5	2
2	(Invited) Metallic Contamination Issues in Advanced Semiconductor Processing. ECS Meeting Abstracts, 2018, , .	0.0	1
3	Depth Profile Analysis of Metals Gettered by Oxide Precipitates in Silicon Substrates. ECS Journal of Solid State Science and Technology, 2017, 6, P231-P234.	1.8	3
4	Depth Profile Analysis of Metals Gettered By Bulk Micro-Defects (BMDs) in Silicon Substrates. ECS Meeting Abstracts, 2016, , .	0.0	0
5	Behavior of Transition Metals Penetrating Silicon Substrate through SiO ₂ and Si ₃ N ₄ Films by Arsenic Ion Implantation and Annealing. ECS Journal of Solid State Science and Technology, 2015, 4, P131-P136.	1.8	18